

STANDARDS WATCH

Volume 17, Issue 1



From the Director's Desk
James Amano, Senior Director

SEMI Publishes First Cybersecurity Standards

To help protect against future cyberattacks on factory equipment, SEMI launched two major Standards Program initiatives that led to the publication of two new standards. [Read more >>](#)

SEMI Taiwan Sets Out to Help Secure Chip Manufacturing Supply Chain with Publication of First Fab Equipment Cybersecurity Specification

In a key step to secure semiconductor manufacturing data traversing the supply chain, SEMI published a specification designed to help protect semiconductor manufacturing data. [Read more >>](#)

Newly Published Standard on Data Sharing and Streaming

The Rich Interactive Test Database (RITdb) Task Force presents its first Standard introducing the RITdb system. [Read more >>](#)

New Proposal for Test Method for Quantifying Basal Plane Dislocations in 4H-SiC by X-ray Topography

Nondestructive test method for analyzing defect in silicon carbide substrates. [Read more >>](#)

300 mm Tape Frame FOUP Related Standards Published

Newly published SEMI E184 and SEMI E185 are sealed containers based on the same concept as the 300 mm FOUP standard known as SEMI E47.1. [Read more >>](#)

New China Advanced Backend Factory Integration Task Force

A new Information & Control Task Force aims to contribute to Backend Factory Standards. [Read more >>](#)

SEMICON Japan Standards Awards

SEMI honored industry leaders for their outstanding accomplishments in developing Standards for the electronics and related industries. [Read more >>](#)

Startups for Semiconductor Sustainability Finalists Announced in Next Step to Greener Chip Industry

SEMI member companies joined forces to seek out and partner with the world's top startups to bring new sustainability technologies to semiconductor operations. [Read more >>](#)

CALENDAR

- March 18 [Environmental Sustainability Forum](#)
- March 28-31 [NA Standards Spring Meetings](#)

Get your 30-Day SEMIViews Trial today!